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Substitute for form 1449B/PTO				Complete if Known			
				Application Number	09/648,861		
INFO	DRMATION	A DI	SCLOSURE	Filing Date	August 25, 2000		
STA	TEMENT	BY A	APPLICANT	First Named Inventor	Sarthi et al.		
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	(use as many s	heets a	as necessary)	Examiner Name	FRENEL VANEI		
Sheet	.2	of	2	Attorney Docket Number	DB000877-000		

Examiner Initials*	Cite No.1									
VF		RAJIV D. BANKER et al., "Relevant Costs, Congestion and Stochasticity in Production Environments", Journal of Accounting and Economics, October 1987, pp 171-197, Elsevier Science Publishers, North BALA V. BALACHANDRAN et al, "On the Efficiency of Cost-Based Decis	lol. Lon							
	-	Rules for Capacity Planning", The Accounting Review, Vol. 72, No. 4 Oct. 1997, pp. 599-619 ROBERT S. KAPLAN, "In Defense of Activity-Based Cost Management", Management Accounting, November 1992, pp/ 58-63	,							
		ROBIN COOPER et al., "Measure Costs Right: Make the Right Decisions' Harvard Business Review, September-October 1988, pp. 96-103								
		R.S. KAPLAN et al., "The Promise and Peril of Integrated Cost System Harvard Business Review, September-October 1995,								
		SRIKANT DATAR et al., "Aggregation, Specification and Measurement Errors in Product Costing", The Accounting Review, Vol. 69, No. 4 October 1994, pp. 567-591								
		R.S. KAPLAN et al., "Overhead Allocation via Mathematical Programm Models", The Accounting Review, April, pp. 352-364, 1971	ing							
V.F		MICHAELPALLES et al., "Strategic Transfer Pricing", Management Science, 44, pp. 451-461, 1998	1 1							
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Examiner Considered Signature *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not

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	Sheet	1	of	2	Attorney Docket Number	DB000877-000		J

U.S. PATENT DOCUMENTS							
Examiner	Cite	U.S. Patent	t Document	Name of Patentee or Applicant	Date of Publication of	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
Initials*	No.1	Number	Kind Code ² (if known)	of Cited Document	Cited Document MM-DD-YYYY		
V.F		5,799,2	86	Morgan et al.	08-25-1998		
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FOREIGN PATENT DOCUMENTS											
Examiner	Cite	F	oreign Patent Do		Name of Patentee or	Date of Publication of	Pages, Columns, Lines, Where Relevant				
Initials*	No.1	Office ³	Number ⁴	Kind Code ⁵ (if known)	Applicant of Cited Document	Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear	1 _e			
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